

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY. DOCKET NO. M122-2515	PRIORITY SERIAL NO. 10441354	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Cem Basceri et al.		
					PRIORITY FILING DATE May 21, 2003	PRIORITY GROUP 2515	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
MM	AA	5,292,673	03-1994	Shinriki et al.			
MM	AB	5,486,488	01-1996	Kamiyama			
MM	AC	5,641,702	06-1997	Imai et al.			
MM	AD	5,726,083	03-1998	Takaishi			
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MM	AJ	6,511,896	1/28/03	Basceri et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AK						No
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
MM	AM			Bin Yu, et al., "70nm MOSFET with Ultra-Shallow, Abrupt, and Super-Doped S/D Extension Implemented by Laser Thermal Process (LTP)", IEEE, 03/1999.			
MM	AN			Somit Talwar, et al., "Ultra-Shallow, Abrupt, and Highly-Activated Junctions by Low-Energy Ion Implantation and Laser Annealing", Verdant Technologies, San Jose, CA.			
MM	AO			Ken-ichi Goto, et al., "Ultra-Low Contact Resistance for Deca-nm MOSFETs by Laser Annealing", IEEE, 09/1999, pps. 20.7.1-20.7.3.			
EXAMINER	Renee May			DATE CONSIDERED 16-1-04			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2515	SERIAL NO. 10/810,778		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Cem Basceri et al.			
				FILING DATE March 25, 2004		GROUP 2818	
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
CD	AA	4,450,041	03/84	Alduff	—	—	—
	AB						
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	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Page, Etc.)							
	AR						
	AS						
EXAMINER	DATE CONSIDERED						
Adsermy	10-1-04						
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